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 Inputs Are TTL-Voltage Compatible Permit Multiplexing From N Lines to 1 Line 	D OR N PACKAGE (TOP VIEW)		
Perform Parallel-to-Serial Conversion			
 Strobe Line Provided for Cascading (N Lines to N Lines) 	B [2 15] 1C1 1Y [3 14] 1C2		
 Flow-Through Architecture Optimizes PCB Layout 	GND [] 4 13]] 1C3 2Y [] 5 12] V _{CC}		
 Center-Pin V_{CC} and GND Pin Configurations Minimize High-Speed Switching Noise 	1 OE 6 11 2C0 2 OE 7 10 2C1 2 C3 8 91 2C2		
 EPIC ™ (Enhanced-Performance Implanted CMOS) 1-µm Process 			

- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, and Standard Plastic 300-mil DIPs

description

Each of these data selectors/multiplexers contains inverters and drivers to supply full binary-decoding data selection to the AND-OR gates. Separate strobe output-enable (\overline{OE}) inputs are provided for each of the two four-line sections.

	(each multiplexer)										
SELECT	INPUTS	[DATA I	NPUTS	STROBE	OUTPUT					
В	Α	C0	C1	C2	C3	OE	Y				
Х	Х	Х	Х	Х	Х	Н	Н				
L	L	L	Х	Х	Х	L	н				
L	L	н	Х	Х	Х	L	L				
L	Н	Х	L	Х	Х	L	н				
L	Н	Х	Н	Х	Х	L	L				
Н	L	Х	Х	L	Х	L	н				
Н	L	Х	Х	Н	Х	L	L				
Н	Н	Х	Х	Х	L	L	н				
Н	Н	Х	Х	Х	Н	L	L				

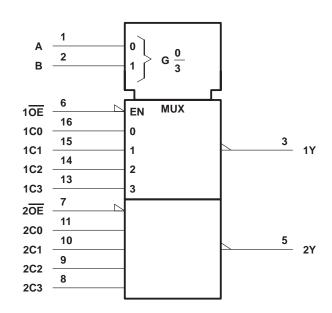
FUNCTION TABLE

The 74ACT11352 is characterized for operation from -40° C to 85° C.

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logic symbol[†]

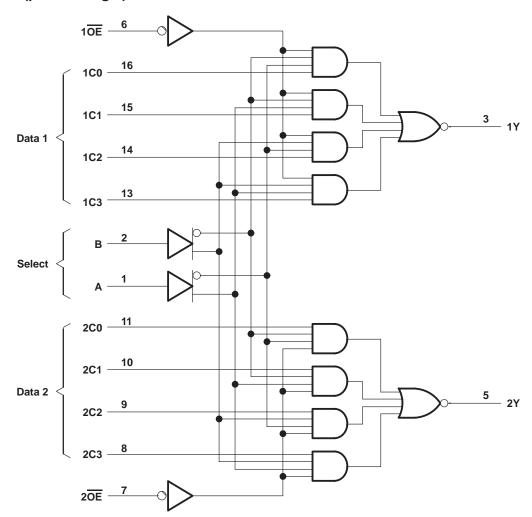


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

	÷ ·
Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	-0.5 V to V_{CC} + 0.5 V
Output voltage range, V _O (see Note 1)	0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	
Continuous output current, I_{O} (V _O = 0 to V _{CC})	±50 mA
Continuous current through V _{CC} or GND pins	±100 mA
Storage temperature range	

⁺ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



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recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
VI	Input voltage	0		VCC	V
VO	Output voltage	0		VCC	V
IOH	High-level output current			-24	mA
IOL	Low-level output current			24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	ns/V
TA	Operating free-air temperature	-40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vcc	T _A = 25°C			MAINI	MAY	LINUT
	TEST CONDITIONS		MIN	TYP	MAX	MIN	MAX	UNIT
	10.0. 50.00	4.5 V	4.4			4.4		V
VOH	I _{OH} = -50 μA	5.5 V	5.4			5.4		
	1	4.5 V	3.94			3.8		
	I _{OH} = -24 mA		4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	I _{OL} = 50 μA I _{OL} = 24 mA	4.5 V			0.1		0.1	V
		5.5 V			0.1		0.1	
VOL		4.5 V			0.36		0.44	
		5.5 V			0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
Ц	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1	μA
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			8		80	μA
ΔI_{CC}^{\ddagger}	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			0.9		1	mA
Ci	$V_I = V_{CC}$ or GND	5 V		3.5				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	T _A = 25°C			MIN	мах	UNIT
FARAMETER	(INPUT)		MIN	TYP	MAX		IVIAA	UNIT
^t PLH	A or B	V	2	5.3	7.8	2	8.6	00
^t PHL		l í ľ	2.9	6.7	9.3	2.9	10.7	ns
^t PLH	Any C	V	2.1	5	7.2	2.1	8.2	20
^t PHL		T	3.3	6.3	7.8	3.3	8.9	ns
^t PLH	OE	V	2	4.2	5.5	2	6	ns
^t PHL			2.5	5.5	7.6	2.5	8.3	115

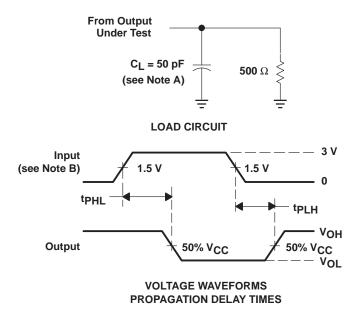


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operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	30	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. CL includes probe and jig capacitance.

B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_Q = 50 Ω , t_f = 3 ns, t_f = 3 ns.

C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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